



REPLACEMENT SHEET

AFTER JOINING

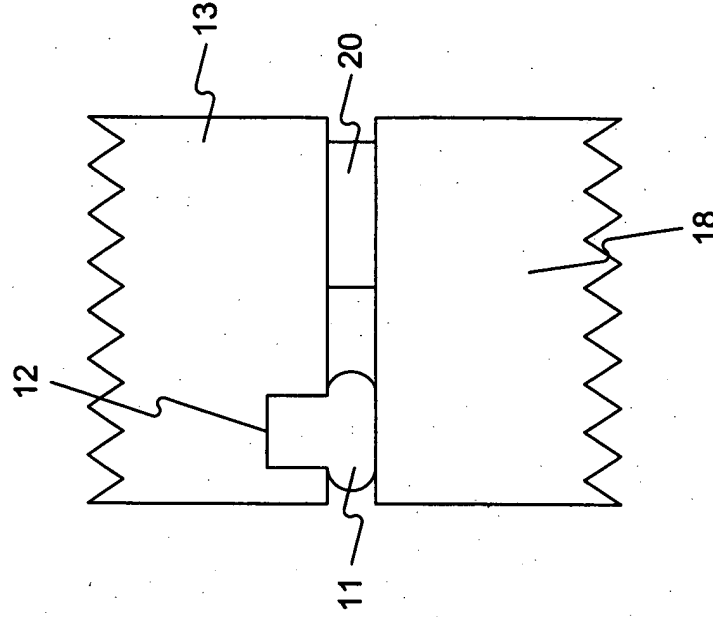


FIG. 1B

BEFORE JOINING

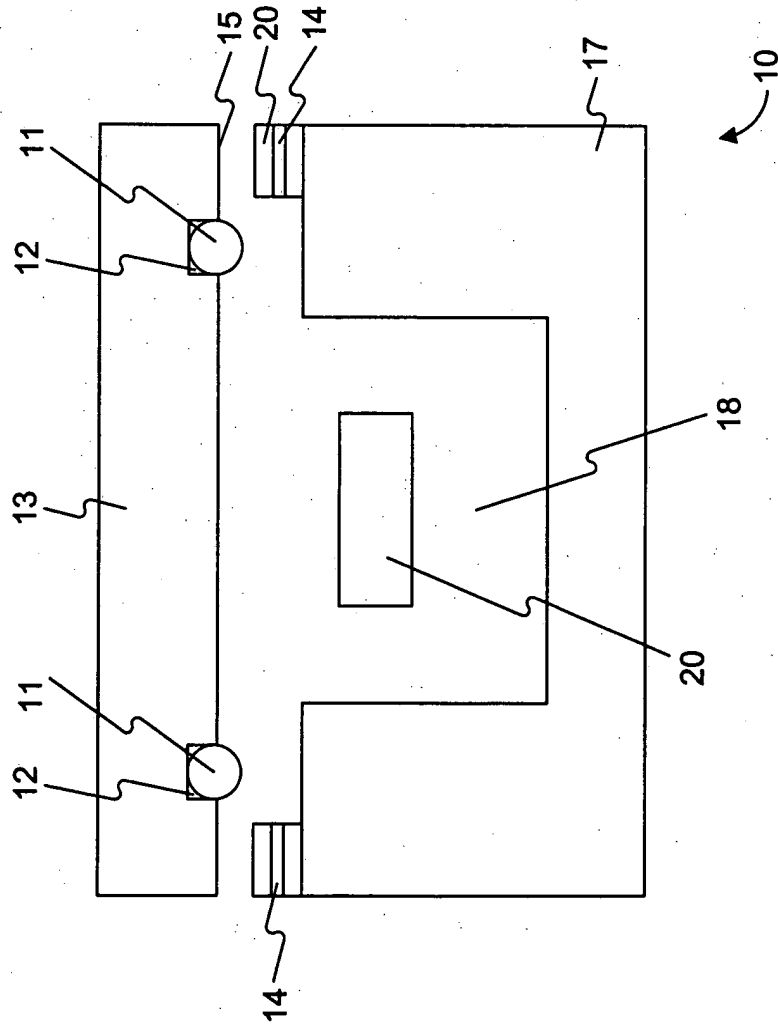


FIG. 1A

REPLACEMENT SHEET

AFTER JOINING

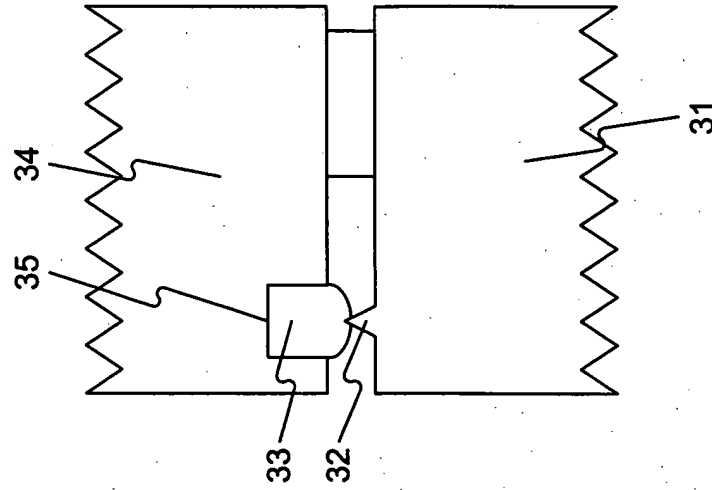


FIG. 2B

BEFORE JOINING

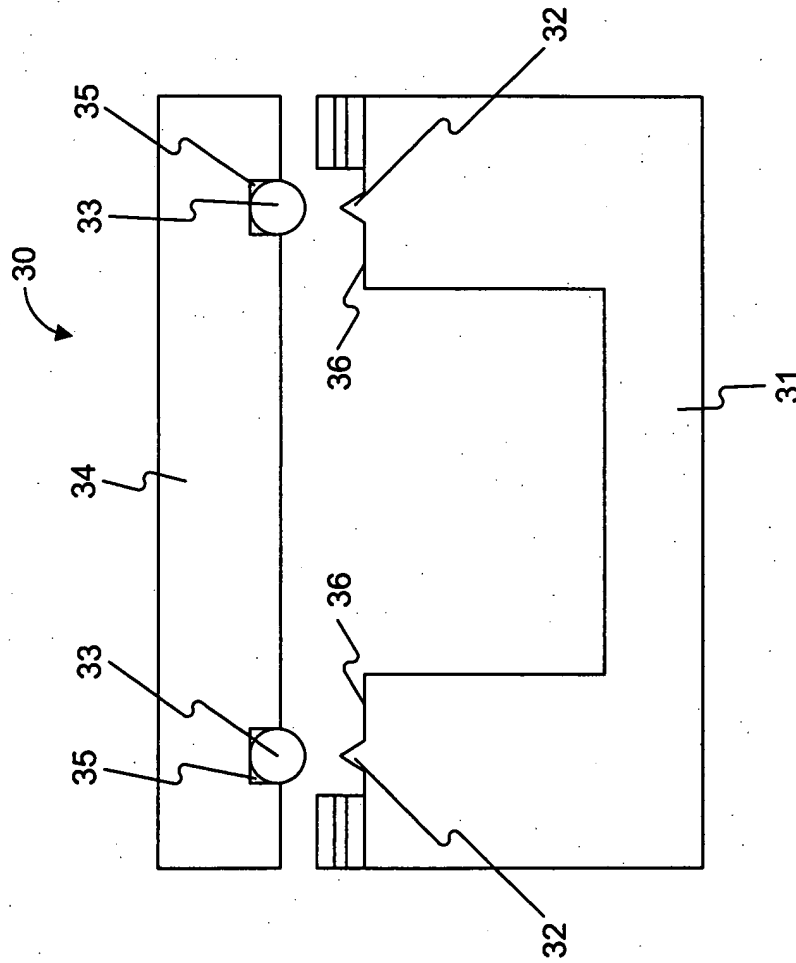


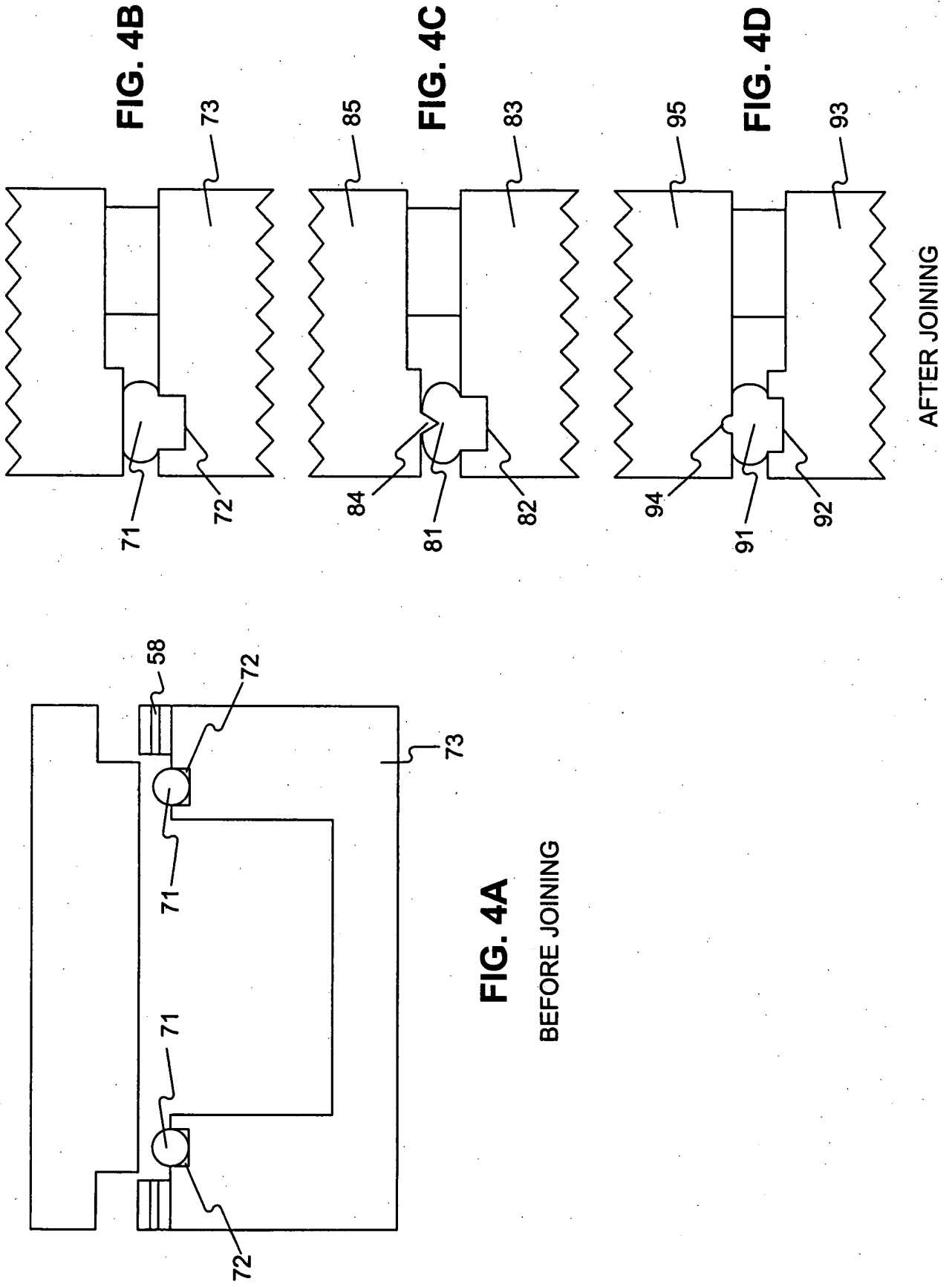
FIG. 2A

Figure 1 consists of two cross-sectional views of a semiconductor device, labeled "BEFORE JOINING" (left) and "AFTER JOINING" (right).

BEFORE JOINING: This view shows a substrate 55 with a central rectangular region 54. On the left side of region 54, there is a structure 56 with a top surface 57. A circular feature 51 is located on the top surface 57. To the left of the circular feature 51 is a layer 52, and to the right is a layer 53. A curved arrow 50 indicates a rotation or movement of the structure 56.

AFTER JOINING: This view shows the same substrate 55 and central region 54. The structure 56 is now joined to the substrate 55. The top surface 57 is now a flat surface. The circular feature 51 is still present. The layers 52 and 53 are still present on the left side of the structure 56.

FIG. 3A



AFTER JOINING

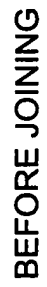


FIG. 5A

BEFORE JOINING

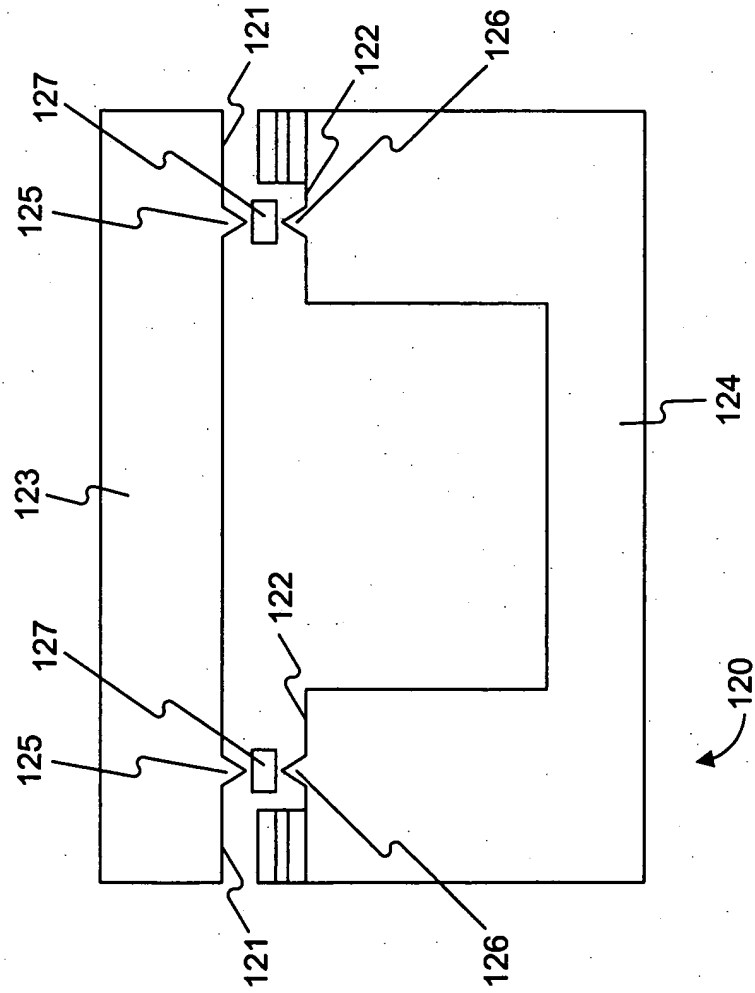


FIG. 6A

AFTER JOINING

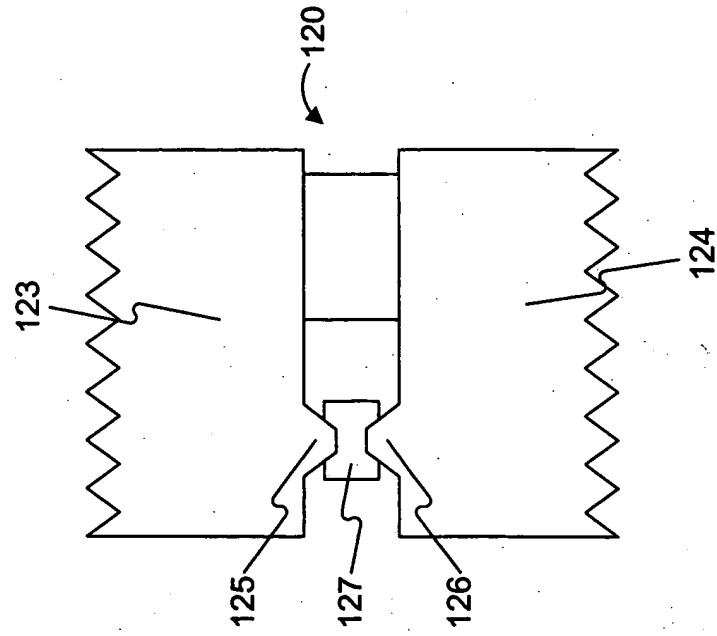


FIG. 6B

REPLACEMENT SHEET

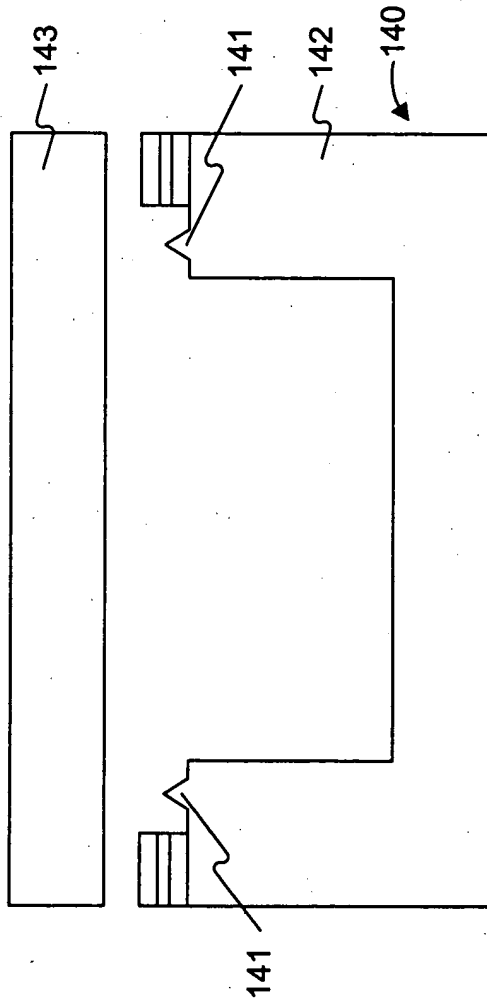


FIG. 7A

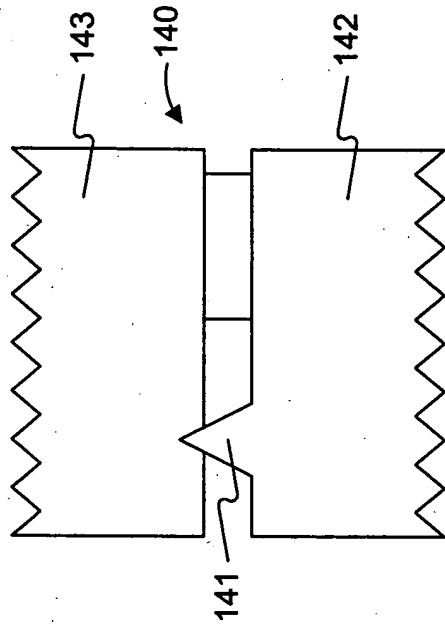


FIG. 7B

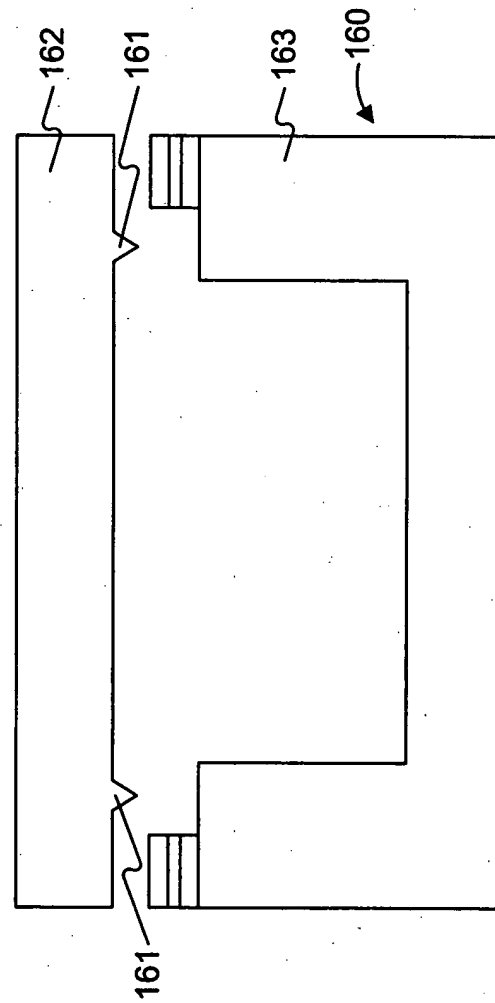


FIG. 7C

BEFORE JOINING

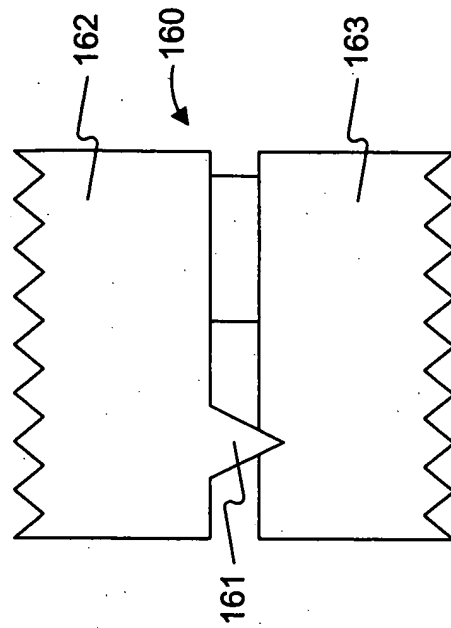


FIG. 7D

AFTER JOINING

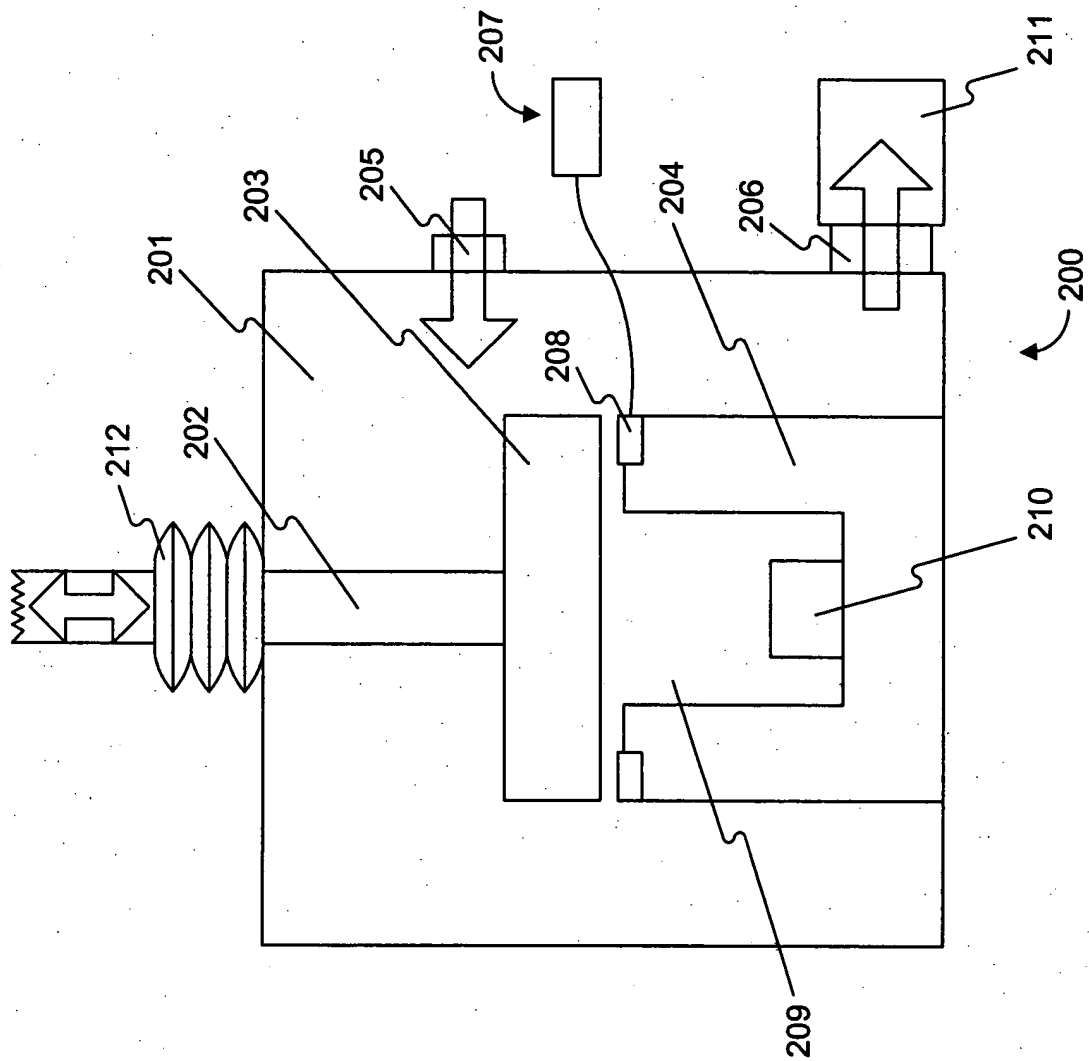


FIG. 8